

Electronic Supplementary Information (ESI):

# Photoinduced electron transfer in thin films of porphyrin-fullerene dyad and perylene-tetracarboxydiimide

*Paola Vivo*<sup>\*,a</sup>, *Alexander S. Alekseev*<sup>b</sup>, *Kimmo Kaunisto*<sup>a</sup>, *Oili Pekkola*<sup>a</sup>, *Antti Tolkki*<sup>a</sup>, *Vladimir Chukharev*<sup>a</sup>, *Alexander Efimov*<sup>a</sup>, *Petri Ihalainen*<sup>c</sup>, *Jouko Peltonen*<sup>c</sup>, and *Helge Lemmetyinen*<sup>a</sup>

<sup>a</sup> Department of Chemistry and Bioengineering, Tampere University of Technology,

P.O. Box 541, FI-33101 Tampere, Finland

<sup>b</sup> Prokhorov General Physics Institute, Russian Academy of Sciences, Vavilov St. 38, 119991 Moscow, Russia

<sup>c</sup> Center of Excellence for Functional Materials, Laboratory of Paper Coating and Converting, Åbo

Akademi University, Porthaninkatu 3-5, FI-20500

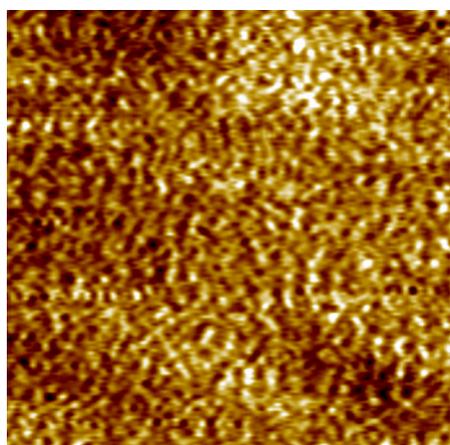
## **Atomic Force Microscopy (AFM)**

---

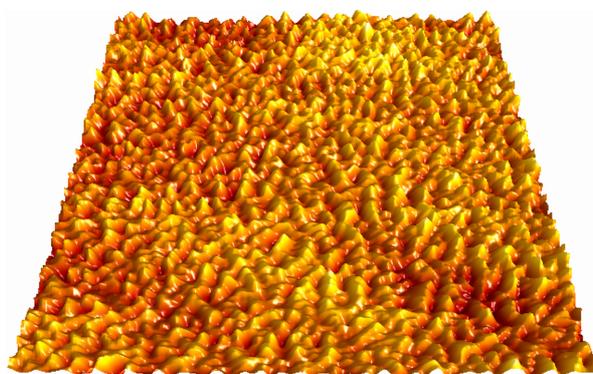
\* To whom correspondence should be addressed. E-mail: [paola.vivo@tut.fi](mailto:paola.vivo@tut.fi). Phone: +358 (0)40 1981 128. Fax: +358 3 3115 2108.

AFM topographs show that both **P-F** and **PTCDI** form relative smooth and uniform films after deposition (Figure S1 and S2). However, the roughness analysis indicates that the **P-F** film is somewhat rougher compared to **PTCDI** film, resulting a slightly higher RMS-roughness and peak-to-peak distance values. This might be also the reason why randomly organized fine structure is much better resolved for **P-F** (Figure S1).

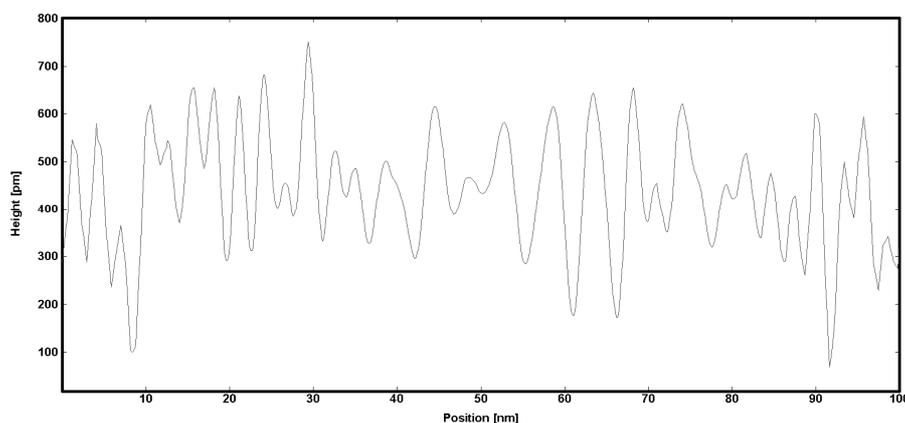
a) **Figures:**



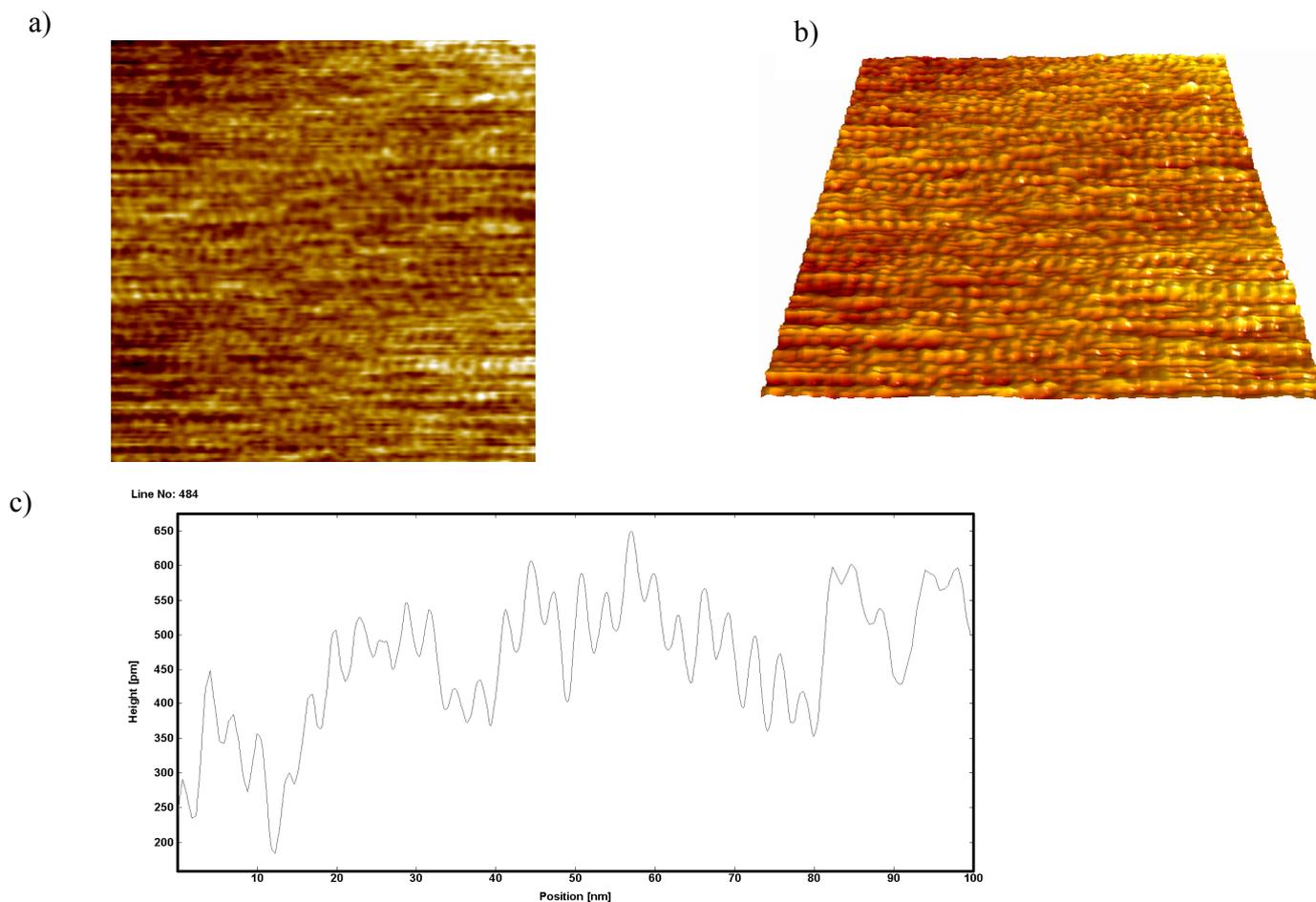
b)



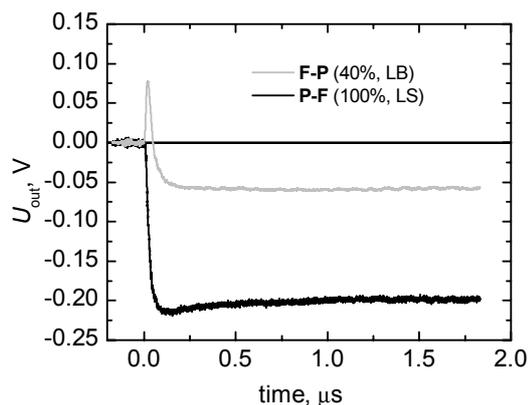
c)



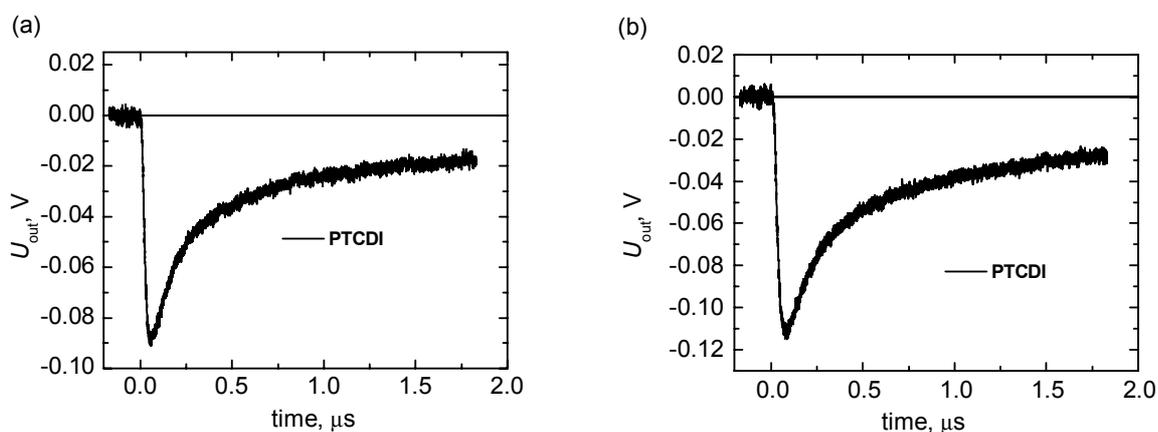
**Figure S1.** AFM images of the 100 mol% **P-F** LS film. (a) Topographic view (image size 100x100 nm<sup>2</sup>) with dark-light height scale 0.7 nm. Root Mean Square (RMS) roughness is 0.108 nm. (b) Isometric view, with 5 x height scaling. (c) Line profile with average peak-to-peak distance  $5 \pm 1$  nm.



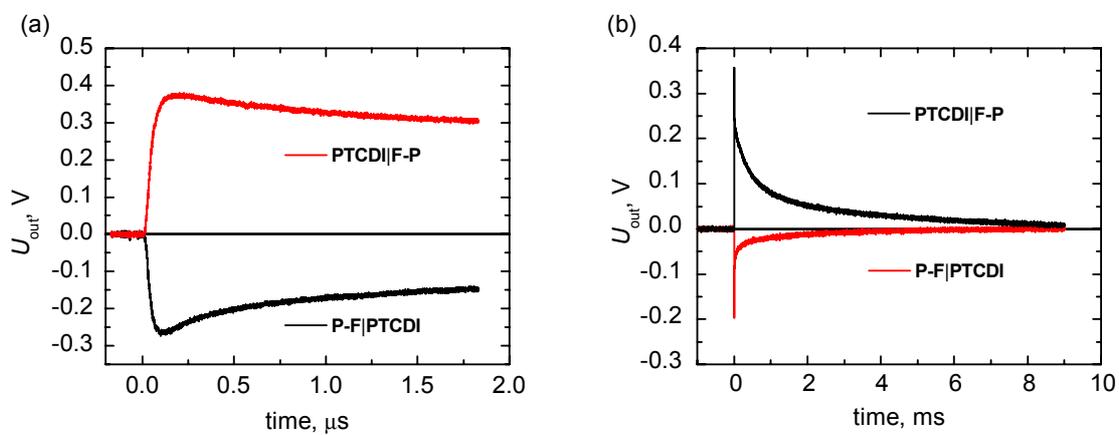
**Figure S2.** AFM images of the thermally evaporated **PTCDI** film. a) Topographic view (image size  $100 \times 100 \text{ nm}^2$ ), with dark-light height scale  $0.7 \text{ nm}$ . Root Mean Square (RMS) roughness is  $0.097 \text{ nm}$ . (b) Isometric view, with  $5 \times$  height scaling. (c) Line profile with average peak to peak distance  $3.5 \pm 0.5 \text{ nm}$ .



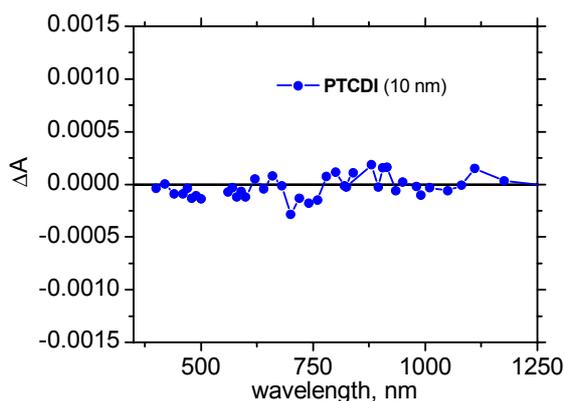
**Figure S3.** Photovoltage (PV) responses of **P-F** (100 mol% LS) and **F-P** (40 mol% LB). The signals are recorded by exciting the samples with  $170 \mu\text{J}/\text{cm}^2$  energy density.



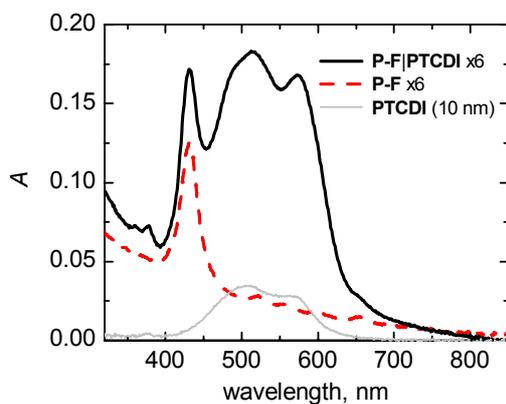
**Figure S4.** Photovoltage (PV) responses of thermally evaporated **PTCDI** (16 nm) at 430 nm excitation wavelength (a), and 532 nm excitation (b). The excitation energy density is  $1.19 \mu\text{J}/\text{cm}^2$ .



**Figure S5.** Photovoltage (PV) responses in short time scale up to 1.8  $\mu\text{s}$  (a), and long time scale up to 9 ms (b) for the bilayer structures **P-F|PTCDI** and **PTCDI|F-P**. The excitation wavelength is 532 nm and the excitation energy density  $0.33 \mu\text{J}/\text{cm}^2$ .



**Figure S6.** Time-resolved absorption spectrum of **PTCDI** film (thickness = 10 nm), at 5  $\mu\text{s}$  after the excitation. The excitation wavelength is 532 nm and the excitation energy density is roughly  $2 \mu\text{J}/\text{cm}^2$ .



**Figure S7.** Absorption spectra of the three sample structures used in flash-photolysis experiments: **P-F** (6 LS), **(P-F |PTCDI) x6**, and **PTCDI** (10 nm).